Abstracts

Development of a Coplanar Waveguide Membrane Probe for Non-Destructive Evaluation of Thin Film Structures

E.W. Seltmann, J. Laskar and K. Smith. "Development of a Coplanar Waveguide Membrane Probe for Non-Destructive Evaluation of Thin Film Structures." 1996 MTT-S International Microwave Symposium Digest 96.3 (1996 Vol. III [MWSYM]): 1411-1414.

A novel prototype membrane coplanar waveguide probe (MCPW) has been designed and fabricated to characterize the dielectric properties of multi-layer thin film structures. The MCPW provides a convenient non-destructive technique to extract the dielectric properties of substrates as thin as 5 mils to 20 GHz. We present the design and analysis of the MCPW and demonstrate feasibility of this new approach.

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